CMSE 2017

Program Book



21st Annual

Components for Military & Space Electronics Conference & Exhibition

April 11-13th, 2017

Four Points by Sheraton (LAX) Los Angeles, California



Workmanship Standards eBook: Hybrids, Microcircuits and RF/MMIC Modules

This is an online illustrated guide depicting photos of common workmanship defects as seen during production and each defect slide is tied



to a particular page in MIL-STD-883. Its intended as an on-the-floor working document for operators, inspectors and quality engineers to facilitate an understanding of defects generated during the manufacture of hybrids, microcircuits and RF/MMIC modules and how they relate to the contractual requirements of MIL-STD-883.

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CMSEWORK20

Welcome to CMSE 2017

Dear Military and Space Electronics Professionals,

On behalf of the Program Committee I would like to personally welcome everyone to this year's 21st annual CMSE Conference and Exhibition. This is in interactive event that requires full participation from the attendees as well as the speakers and exhibitors. The idea is to promote broad discussion about grass root technical issues we all face together in this industry. So please take the time to listen, ask good questions and don't hesitate to respectfully challenge each other's ideas and technical opinions.

I'd like to personally thank our sponsors and exhibitors for supporting CMSE. On a programming note an electronic copy of all the presentations will be sent via a secure link to all attendees after completion of CMSE 2017.

I look forward to speaking to each and everyone, welcome!

Tom Green

Program Chairman

Program Committee

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Bob Lowry
Electronic Materials Consultant

Mike McKeown
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Mike Sampson NASA

Jeff Sokol The Aerospace Corp.

Tom Terlizzi
TJ Green Associates LLC



Keynote Speakers

Michael J. Sampson received his MSc in Engineering Management from the University of Maryland, University College, in 1999. He has been co-Manager of the NASA Electronic Parts and Packaging (NEPP) Program since October 1, 2003 and GSFC Alert Coordinator since 2005. The NEPP program is a cross-agency activity that evaluates new and emerging EEE part technologies, shares information and develops tools for EEE parts assurance. Mike has worked for NASA for over 20 years. Before joining NASA, Mike spent five years as a NASA support contractor and before that, more than twenty years as an engineer and engineering manager in electronic parts manufacturing.

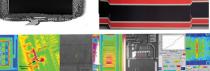
David Davis is currently the SMC Chief Systems Engineer at the Space and Missile Systems Center, Air Force Space Command, Los Angeles Air Force Base, CA. He has also served as the Acting Engineering Director. Mr Davis is in his 39th year at SMC where he spent the first ten years supporting the Global Positioning System (GPS) Program and Defense Meteorological Satellite Program (DMSP) working primarily satellite hardware design, manufacturing, quality and test. In his role, he supports the Commander and the Director of Engineering for center wide application of systems engineering, parts, materials and processes, radiation hardening, specifications and standards, industrial base, manufacturing/quality engineering, and space flight worthiness assessment.

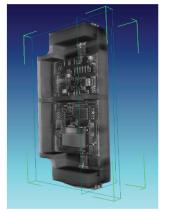
OMPONENT TEST AND ANALYSIS LABORATORIES

The Raytheon Component Test and Analysis Lab is a A full-service facility for evaluating, testing, and performing root cause failure analysis on components for commercial, airborne, military, space and other applications. Analysis team specializes in working with electronic and mechanical components such as hybrids, connectors cables, harnesses, passive or discrete components, and digital or linear devices. With access to a detailed database containing more than 30 years of test and analysis data, our team is able to contribute a wealth of experience and insight when assessing









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20 17 Event Schedule

	TRAINING SEMINARS				
	0700 - 0800	BREAKFAST AND REGISTRATION			
TUESDAY	0800 - 1200	Session A Hermeticity Testing, RGA and the New TM 1014 Spec Limits	Thomas J Green TJ Green Associates LLC Robert Lowry Electronic Materials Consultant		
		Session B Multi Layer Ceramic Capacitor TechnologyMaterials, Processes and Reliability	John Marshall AVX Corp		
	1300 - 1700	Session A Non-Hermetic Packaging for Hi- Rel Military and Aerospace	Thomas J Green TJ Green Associates LLC Robert Lowry Electronic Materials Consultant		
		Session B Microelectronic Package & Board Failure Mechanisms and Related Analysis Techniques	Steve Greathouse Plexus Corporation		









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		EXHIBITOR HOURS: 1100 - 1900					
WEDNESDAY	0800 - 0815	Welcome/Intro					
	0815 - 0845	Keynote Echoes Of The Past, Glimpses Of The Future Ongoing Trends In Assurance Of EEE Parts For Spaceflight	Michael J. Sampson NASA Goddard Space Flight Center				
	Session 1 - Hermetic Vs Non-Hermetic PackagingIs Our Fate Sealed?						
	0845 - 0910	1.1 Hermetic and Non-Hermetic QML ICs – Current Status and Challenges	Shri Agarawl NASA JPL				
	0910 - 0935	1.2 COTS & COTS + Tantalum Capacitor Failures Confirm Systemic Moisture Sensitivity Issues	Aaron Dermarderosian Raytheon Space And Airborne Systems				
	0935 - 1000	1.3 The New Tighter Hermeticity Test Leak Requirements – European Overview	Gonzalo Fernández Romero Alter Technology				
	1000 - 1015	COFFEE BREAK					
	1015 - 1040	1.4 Hermetic Weld Schedule Optimization Based Tighter TM 1014 Leak Rate Specifications	Rich Richardson Microcircuit Labs LLC				
	1040 - 1105	1.5 Meeting the New Tighter Hermeticity Requirements with Optical Leak Testing (OLT)	Tom Trafford NORCOM				
	1105 - 1130	1.6 Gross Leak Standards Development	Kathy Laird NASA/MSFC				
	1130 - 1200	1.7 Hermetic/Non-Hermetic Panel Discussion	Tom Green, Moderator TJ Green Associates LLC				
	1200 - 1400	LUNCH - IN EXHIBITS AREA					
	Session 2 - Passive Components and Packaging Methods for Hi Rel/Space Applications						
	1400 - 1425	2.1 Degradation and ESR Failures in MnO2 Chip Tantalum Capacitors	Alexander Teverovsky ASRC Federal Space and Defense				
	1425 - 1450	2.2 Tantalum Polymer Capacitors: COTS plus Solutions for Space Applications	Chris Reynolds AVX				
	1450 - 1515	2.3 Polymer Tantalum Capacitors Under Vacuum	Michael Cozzolino Raytheon Systems				
	1515 - 1540	2.4 Advanced Polymer Capacitors	Chuck Pothier Vishay				
	1540 - 1600	COFFEE BREAK					
	1600 - 1625	2.5 Hermetic Tantalum Caps for High Power Pulse Applications	Charlie Dewey Evans Capacitor Company				
	1625 - 1650	2.6 Base Metal Ceramic Capacitors for High Reliability Applications	John Marshall AVX				
	1650 - 1715	2.7 A Low Profile High Power Inductor for High Reliability Applications	David Olson Vishay				
	1715 - 1740	2.8 Polymer Tantalum Capacitors for Use in Mission Critical Applications	Ed Jones				
	1715 - 1740	, , , , , , , , , , , , , , , , , , ,	KEMET Electronics Corporation				

17 Event Schedule

	EXHIBITOR HOURS: 1000 - 1400					
	0800 - 0830	Keynote Challenges for Future Space Systems Acquisitions	Dave Davis USAF SMC			
THURSDAY	Session 3 - Copper Wire Bonding for High Reliability Applications					
	0830 - 0855	3.1 Introduction of High Reliability Copper Bonding Wire for High Rel Industrial, A&D Automotive Applications	William (Bud) Crockett, Jr. Tanaka Denshi Group Saga			
	0855 - 0920	3.2 A Review on Copper Wirebond Technology in PEMs	Dr. Mukul Saran, QRE Texas Instruments			
	0920 - 0945	3.3 Assessment of Copper Bond Wire for Use in Long Term Military Applications	Aaron Lecomte Raytheon Integrated Defense Systems			
	0945 - 1010	3.4 Decapsulation of Copper Wire Bonded Devices	Subramani Manoharan CALCE	Patrick Cluskey University of Maryland		
	1010 - 1030	COFFEE BREAK				
	1030 - 1055	3.5 CU Bond Wire Reliability & Decapsulation Process	S. Ali Lilani Integra Technologies LLC	Gary Downing Analytical Solutions		
	1050 - 1115	3.6 Flexible Copper Welded Interconnects for Crosstalk Reduction in WBG Power Modules	Dr. Doug Hopkins and Adam Morgan NC State	Mike McKeown Hesse-Mechatronics		
	1115 - 1140	3.7 High Performance Packaging for Space	Arne K. Knudsen Kyocera America Inc.			
	1140 - 1205	3.8 High Reliability Rad Hard e-Mode Gallium Nitride HEMT GaN Power Technologies & Packaging for Space	Jim Larrauri Freebird Semiconductor			
	1205 - 1330	LUNCH - IN EXHIBITS AR	AREA			
	Session 4 - COTS: SUCCESS STORIES AND CHALLENGES					
	1330 - 1355	4.1 Understanding PCB Design & Material Warpage Challenges which Occur during B2B Board-to-Board/Module-Carrier Attachment	Eric Moen Akrometrix			
	1355 - 1420	4.2 3D Digital Stitching in the Electronics World and Its Use with Dendritic Growth Studies	Steve Greathouse Plexus Corporation			
	1420 - 1445	4.3 HALT Testing for Use of COTS Parts on NASA Missions	Anupam Choubey NASA JPL			
	1445 - 1510	4.4 Deployed Forensic Cloud-Based Track and Trace Platform for Microcircuits	Bob MacDowell Applied DNA Sciences			
	1510 - 1530	BREAK				
	Session 5 - OBSOLETE COMPONENTS and COUNTERFEIT PARTS					
	1530 - 1555	5.1 A Counterfeit Component Case History	Bob Lowry Electronic Materials Consultant			
	1555 - 1620	5.2 Integrated Circuit Redesign Obsolescence: Assembly Options and Solutions	Tim Flaherty Golden Altos			
	1620 - 1645	5.3 Implications of COTS Packaging Modifications in Legacy Systems	Aaron DerMarderosian Raytheon Space and Airborne Systems			
	1645 - 1710	5.4 Risks with Obsolete Military Marked Components from the Open Market	Leon Hamiter Components Technology Ins	titute Inc		



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Job Description

Job Title: Senior Component/EEE Parts Engineer (660263)

Job ID: 660263 Location: CO - Boulder

Full/Part Time: Full-Time Regular/Temporary: Regular

Lead and work with Parts, Radiation and Reliability engineers to support design teams in the selection, evaluation, analysis and documentation of Electrical, Electronic, and Electromechanical (EEE) parts.

What you'll do:

- Perform Parts, Radiation and Reliability Engineering functions on complex programs using proven industry techniques and principles:
 - o Evaluate EEE parts against aerospace program screening, and qualification, and component level radiation SEE and TID requirements.
 - o Leverage and maximize company standard parts library usage across programs & product class.
 - o Process Non-Standard Part Approval Requests.
 - o Assist Design Engineering with part and vendor selections.
 - o Work with a Parts Control Board to approve EEE parts;
 - o Maintain and update Program Approved Parts Lists to meet requirements and maximize company standard parts library usage.
 - o Generate part drawings for non-standard parts only.
 - o Review new GIDEP Advisories and Alerts for program impact.
 - o Write and present reports documenting analysis results and anomaly results.
- Lead the Parts/Radiation/Reliability Engineering effort on aerospace programs:
 - o Interface with program personnel such as designers, customers, suppliers, management, and mission assurance disciplines to provide low cost solution.
 - o Translate customer requirements into internal procedures through the construction of a plan, based on BPL (Ball Process Libraries) and ISO processes.
 - o Plan, direct, and review efforts of other component engineers to support the program requirements while working to cost and schedule constraints.

What you'll need:

- BS in Electrical Engineering or a related technical field is required, plus 8 or more years of related experience.
- 8 or more years of continuous, related, progressive experience in the parts/radiation/ reliability engineering discipline is desired. Strong expertise in one or more domains and reasonable knowledge regarding other domains will also be considered.
- Collaborative working skills with programs, cross disciplinary teams and with management.
- Should have or must be able to obtain a TS/SCI clearance.

2017 **Exhibitors**

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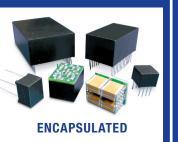




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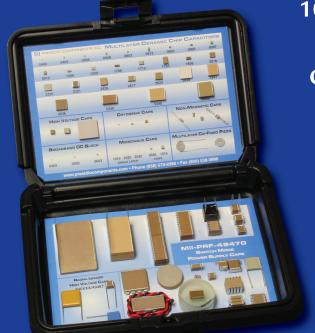
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